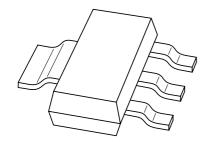
## **DISCRETE SEMICONDUCTORS**

## DATA SHEET



# PBSS5540Z40 V low V<sub>CEsat</sub> PNP transistor

Product data sheet Supersedes data of 2001 Jan 26



## 40 V low V<sub>CEsat</sub> PNP transistor

#### PBSS5540Z

#### **FEATURES**

- Low collector-emitter saturation voltage
- · High current capability
- Improved device reliability due to reduced heat generation.

#### **APPLICATIONS**

- Supply line switching circuits
- · Battery management applications
- DC/DC converter applications
- · Strobe flash units
- Heavy duty battery powered equipment (motor and lamp drivers)
- MOSFET driver applications.

#### **DESCRIPTION**

PNP low  $V_{CEsat}$  transistor in a SOT223 plastic package. NPN complement: PBSS4540Z.

#### **MARKING**

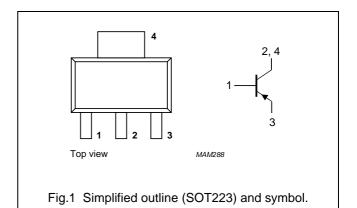
TYPE NUMBER	MARKING CODE
PBSS5540Z	PB5540

#### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX	UNIT
V <sub>CEO</sub>	emitter-collector voltage	-40	V
I <sub>C</sub>	collector current (DC)	-5	Α
I <sub>CM</sub>	peak collector current	-10	Α
R <sub>CEsat</sub>	equivalent on-resistance	<80	mΩ

#### **PINNING**

PIN	DESCRIPTION
1	base
2	collector
3	emitter
4	collector



## 40 V low V<sub>CEsat</sub> PNP transistor

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#### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CBO</sub>	collector-base voltage	open emitter	_	-40	V
$V_{CEO}$	collector-emitter voltage	open base	_	-40	V
V <sub>EBO</sub>	emitter-base voltage	open collector	_	-6	V
I <sub>C</sub>	collector current (DC)		-	-5	Α
I <sub>CM</sub>	peak collector current		_	-10	Α
I <sub>BM</sub>	peak base current		_	-2	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> ≤ 25 °C; note 1	-	1.35	W
		T <sub>amb</sub> ≤ 25 °C; note 2	-	2	W
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>j</sub>	junction temperature		_	150	°C
T <sub>amb</sub>	operating ambient temperature		-65	+150	°C

#### **Notes**

- 1. Device mounted on a printed-circuit board, single-sided copper, tinplated, mounting pad for collector 1 cm<sup>2</sup>.
- 2. Device mounted on a printed-circuit board, single-sided copper, tinplated, mounting pad for collector 6 cm<sup>2</sup>. For other mounting conditions, see *"Thermal considerations for SOT223 in the General Part of associated Handbook"*.

#### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R <sub>th j-a</sub>	thermal resistance from junction to ambient	in free air; note 1	92	K/W

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#### Note

1. Device mounted on a printed-circuit board, single-sided copper, tinplated, mounting pad for collector 1 cm<sup>2</sup>.

## 40 V low $V_{\text{CEsat}}$ PNP transistor

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#### **CHARACTERISTICS**

 $T_{amb}$  = 25 °C unless otherwise specified.

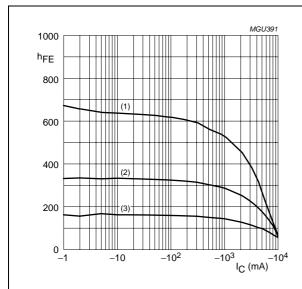
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I <sub>CBO</sub>	collector-base cut-off current	$V_{CB} = -30 \text{ V}; I_E = 0$	_	_	-100	nA
		$V_{CB} = -30 \text{ V}; I_E = 0; T_j = 150 ^{\circ}\text{C}$	_	_	-50	μΑ
I <sub>EBO</sub>	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_C = 0$	-	_	-100	nA
h <sub>FE</sub>	DC current gain	$V_{CE} = -2 \text{ V}; I_{C} = -500 \text{ mA}$	250	350	_	
		$V_{CE} = -2 \text{ V}; I_{C} = -1 \text{ A}; \text{ note 1}$	200	300	_	
		$V_{CE} = -2 \text{ V}; I_{C} = -2 \text{ A}; \text{ note 1}$	150	250	_	
		$V_{CE} = -2 \text{ V}; I_{C} = -5 \text{ A}; \text{ note 1}$	50	150	_	
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_C = -500 \text{ mA}; I_B = -5 \text{ mA}$	-	-80	-120	mV
		$I_C = -1 \text{ A}; I_B = -10 \text{ mA}$	-	-120	-170	mV
		$I_C = -2 \text{ A}; I_B = -200 \text{ mA}$	-	-110	-160	mV
R <sub>CEsat</sub>	equivalent on-resistance	$I_C = -2 \text{ A}$ ; $I_B = -200 \text{ mA}$ ; note 1	-	<55	<80	mΩ
V <sub>CEsat</sub>	collector-emitter saturation voltage	$I_C = -5 \text{ A}; I_B = -500 \text{ mA}$	-	-250	-375	mV
V <sub>BEsat</sub>	base-emitter saturation voltage	$I_C = -5 \text{ A}; I_B = -500 \text{ mA}$	-	_	-1.3	V
$V_{BEon}$	base-emitter turn-on voltage	$V_{CE} = -2 \text{ V}; I_{C} = -2 \text{ A}$	-	-0.8	-1.25	V
f <sub>T</sub>	transition frequency	$I_C = -100 \text{ mA}; V_{CE} = -10 \text{ V};$ f = 100 MHz	60	120	_	MHz
C <sub>c</sub>	collector capacitance	$V_{CB} = -10 \text{ V}; I_E = I_e = 0;$ f = 1 MHz	_	90	105	pF

#### Note

1. Pulse test:  $t_p \le 300~\mu s;~\delta \le 0.02.$ 

## 40 V low V<sub>CEsat</sub> PNP transistor

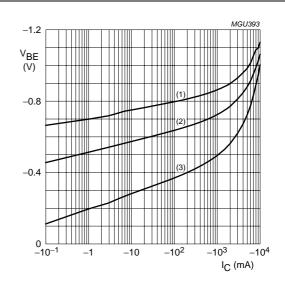
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 $V_{CE} = -2 V$ .

- (1)  $T_{amb} = 150 \, ^{\circ}C$ .
- (2)  $T_{amb} = 25 \, ^{\circ}C$ .
- (3)  $T_{amb} = -55 \, ^{\circ}C$ .

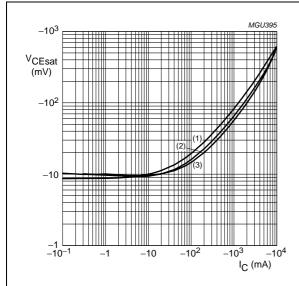
Fig.2 DC current gain as a function of collector current; typical values.



 $V_{CE} = -2 V$ .

- (1)  $T_{amb} = 150 \, ^{\circ}C$ .
- (2) T<sub>amb</sub> = 25 °C.
- (3)  $T_{amb} = -55 \, ^{\circ}C$ .

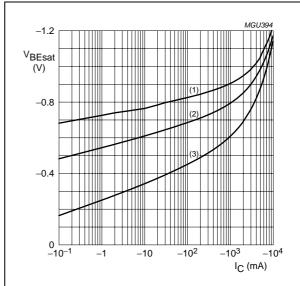
Fig.3 Base-emitter voltage as a function of collector current; typical values.



 $I_{\rm C}/I_{\rm B} = 20.$ 

- (1)  $T_{amb} = 150 \, ^{\circ}C$ .
- (2)  $T_{amb} = 25 \, ^{\circ}C$ .
- (3)  $T_{amb} = -55 \, ^{\circ}C$ .

Fig.4 Collector-emitter saturation voltage as a function of collector current; typical values.



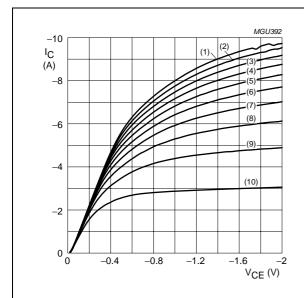
 $I_{\rm C}/I_{\rm B} = 20.$ 

- (1)  $T_{amb} = 150 \, ^{\circ}C$ .
- (2)  $T_{amb} = 25 \, ^{\circ}C$ .
- (3)  $T_{amb} = -55 \, ^{\circ}C$ .

Fig.5 Base-emitter saturation voltage as a function of collector current; typical values.

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 $T_{amb} = 25 \, ^{\circ}C.$ 

(1)  $I_B = -150 \text{ mA}$ .

(5)  $I_B = -90 \text{ mA}.$ 

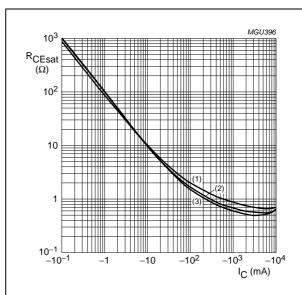
(9)  $I_B = -30 \text{ mA}.$ (10)  $I_B = -15 \text{ mA}.$ 

(2)  $I_B = -135 \text{ mA}.$ (3)  $I_B = -120 \text{ mA}.$  (6)  $I_B = -75 \text{ mA}.$ (7)  $I_B = -60 \text{ mA}.$ 

(4)  $I_B = -105 \text{ mA}$ .

(8)  $I_B = -45 \text{ mA}.$ 

Fig.6 Collector current as a function of collector-emitter voltage; typical values.



 $I_{\rm C}/I_{\rm B} = 20.$ 

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(1)  $T_{amb} = 150 \, ^{\circ}C$ .

(2)  $T_{amb} = 25 \, ^{\circ}C$ .

(3)  $T_{amb} = -55 \, ^{\circ}C$ .

Fig.7 Collector-emitter equivalent on-resistance as a function of collector current; typical values.

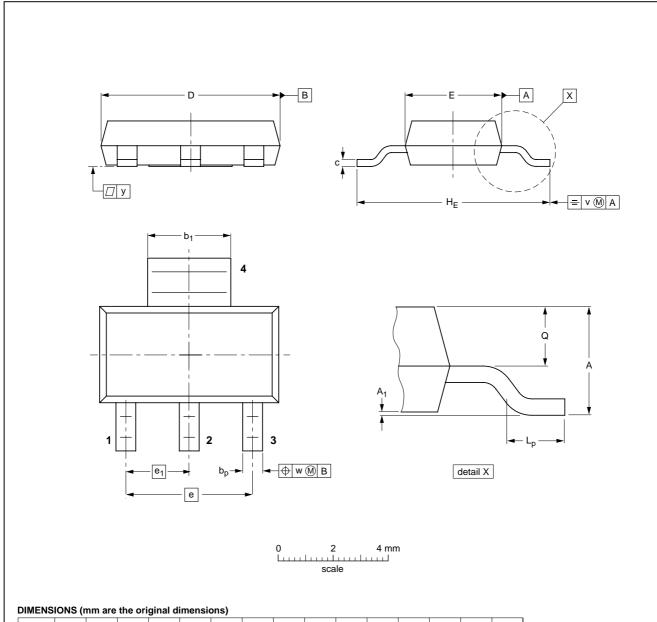
## 40 V low V<sub>CEsat</sub> PNP transistor

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#### **PACKAGE OUTLINE**

Plastic surface mounted package; collector pad for good heat transfer; 4 leads

**SOT223** 



UNIT	Α	A <sub>1</sub>	bp	b <sub>1</sub>	С	D	E	е	e <sub>1</sub>	HE	Lp	Q	٧	w	у
mm	1.8 1.5	0.10 0.01	0.80 0.60	3.1 2.9	0.32 0.22	6.7 6.3	3.7 3.3	4.6	2.3	7.3 6.7	1.1 0.7	0.95 0.85	0.2	0.1	0.1

OUTLINE	REFERENCES EUROPEAN IS					ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT223			SC-73			<del>97-02-28</del> 99-09-13

## 40 V low V<sub>CEsat</sub> PNP transistor

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DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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